

## Theoretical and Experimental Investigations of X-ray Back Diffraction at Grazing Incidence

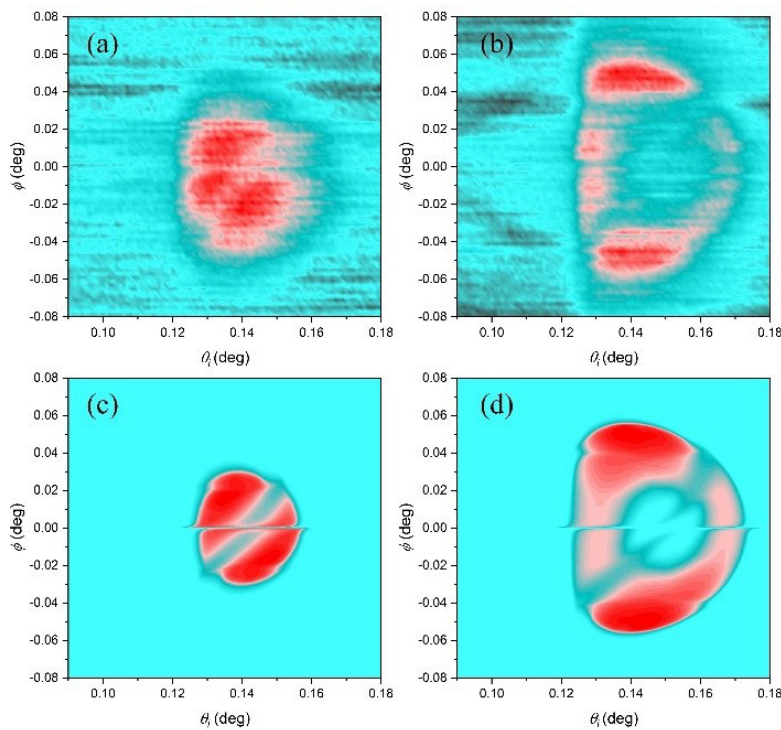
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We report our recent theoretical and experimental investigations on Grazing-Incidence X-ray Back Diffraction (GIXBD) from a highly miscut ( $\theta_m = 89.926^\circ$ ) Si (12 4 0) crystal. The unique optical characteristics of X-ray back diffraction, such as wide angular acceptance and high energy resolution, excited from a highly asymmetric-cut crystal demonstrate significant angular dispersion properties [1], leading to the development of high-resolution monochromators and analysers. [2]. We have recently calculated the 2-beam GIXBD of Si (12 4 0) [3], using a fully dynamical simulation based on the algorithm by Stetsko and Chang [4]. In this paper, the algorithm is applied to compute the complex 24-beam Si (12 4 0), in which 96 eigen modes are excited inside the crystal. Conducted at a sub-meV temporally coherent synchrotron radiation beamline, our experimental results have strongly confirmed our theoretical predictions (refer to Figure 1). The measured angular dispersion rate (ADR)  $44 \pm 9 \mu\text{rad}/\text{meV}$ , which traditional DuMond analysis cannot explain, is several times larger than that of ever reported. This finding indicates a vast potential for the development of advance future X-ray optical devices.



**Figure 1.** The intensity distribution of GIXBD at a miscut angle of  $89.926^\circ$ , plotted as a function of the incident angle ( $\theta_i$ ) and the azimuthal angle ( $\phi$ ), is shown in (a) for an incident energy of 0 meV, and in (b) for an incident energy of 4.9 meV. Fig. (c) and (d) represent the corresponding theoretical simulations based on dynamical X-ray diffraction theory.

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[2] Shvyd'ko, Y., Stoupin, S., Shu, D., Collins, S. P., Mundboth, K., Sutter, J., and Tolkiehn, M. (2014). Nat. Commun. **5**, 4219.

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[4] Stetsko, Y. P. and Chang, S.-L. (1997). Acta Cryst. A **53**, 28.